









Auto Defect Classification

Purpose	Automatic Defect Classification capabilities available in STI optical inspection platforms enabling intelligent defect classification, reducing dependency on manual review and improving yield recovery
Technology	<ol style="list-style-type: none"> 1. Rule Based Auto Classification – Defect classification is based on pre-define rule comparing various defect features and advanced statistical analysis. 2. Zone Based Auto Classification – Defect classification is performed by analyzing defect’s location combined with advanced statistical analysis 3. AI Based Auto Review – Apply Deep Learning/Machine Learning methodologies to eliminate manual defect review

STI Products	Rule Based Auto Classification	Zone Based Auto Classification	AI Based Auto Review
 iFocus – Wafer 2D & 3D Scan			
 Hexa – Tray 2D & 3D Scan			
 tSort - WLP Scan & Sort	